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Titolo	Recent Developments in Atomic Force Microscopy and Raman Spectroscopy for Materials Characterization // edited by Chandra Shakher Pathak and Samir Kumar
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Descrizione fisica	1 online resource (xi, 274 pages) : illustrations
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Sommario/riassunto	This book contains chapters that describe advanced atomic force microscopy (AFM) modes and Raman spectroscopy. It also provides an in-depth understanding of advanced AFM modes and Raman spectroscopy for characterizing various materials. This volume is a useful resource for a wide range of readers, including scientists, engineers, graduate students, postdoctoral fellows, and scientific professionals working in specialized fields such as AFM, photovoltaics, 2D materials, carbon nanotubes, nanomaterials, and Raman spectroscopy.